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... 2A.7 A **Simulation** Analysis of Quarter-Micron CMOS LSI Input Circuit ... Heads as a function of Temperature, C.Moore, **Integral Solutions International**; A. Wallash ...

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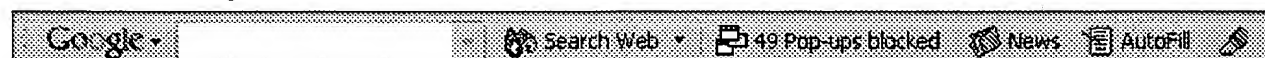
... of GMR Heads subjected to CDM and HBM ESD Events C. Moore, **Integral Solutions International**. ... QST) analysis with in-situ CDM and HBM ESD **simulation** capabilities. ...

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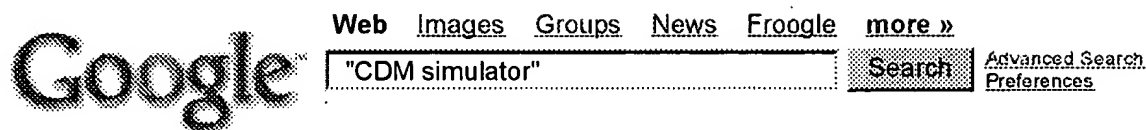


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Development Ref: EEC. 12/2003, Y. Responsible Organisation ...

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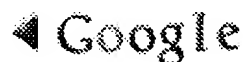
Charged Device

... THE **CDM SIMULATOR**: At a standard charged device modelling simulator the device under test is placed on dielectric, charged by a power supply and discharged ...

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Stepanek, P.; Kurtz, D.; Gorin, J.;

Microwave Symposium Digest, 2003 IEEE MTT-S International , Volume: 2 , 8 June 2003

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Shively, R.R.; Gorin, A.L.;

Acoustics, Speech, and Signal Processing, 1989. ICASSP-89., 1989 International Conference on , 23-26 May 1989

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Nuclear Science, IEEE Transactions on , Volume: 49 , Issue: 3 , June 2002

Pages:950 - 956

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A.; Hasegawa, T.; Matsuda, T.; Kuroda, K.-I.;  
Nuclear Science Symposium Conference Record, 2001 IEEE , Volume: 1 , 4-1  
Nov. 2001  
Pages:559 - 563 vol.1

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**5 Analysis of current distribution in the zone of high speed sliding contact of the pulsed electromechanical converters**

Chemerys, V.T.; Gorin, V.V.;

Pulsed Power Plasma Science, 2001. IEEE Conference Record - Abstracts , 17  
June 2001  
Pages:530

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**6 Adaptive language acquisition using incremental learning**

Farrell, K.; Mammone, R.J.; Gorin, A.L.;

Acoustics, Speech, and Signal Processing, 1993. ICASSP-93., 1993 IEEE  
International Conference on , Volume: 1 , 27-30 April 1993  
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